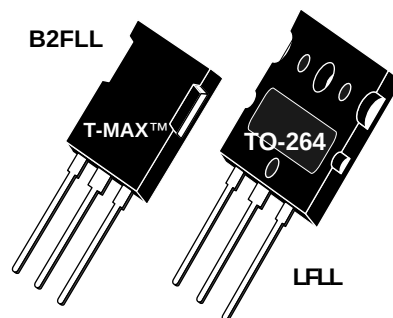
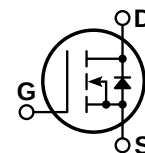


POWER MOS 7® FREDFET

Power MOS 7® is a new generation of low loss, high voltage, N-Channel enhancement mode power MOSFETs. Both conduction and switching losses are addressed with Power MOS 7® by significantly lowering $R_{DS(on)}$ and Q_g . Power MOS 7® combines lower conduction and switching losses along with exceptionally fast switching speeds inherent with APT's patented metal gate structure.



- Lower Input Capacitance
- Lower Miller Capacitance
- Lower Gate Charge, Q_g
- Increased Power Dissipation
- Easier To Drive
- Popular T-MAX™ or TO-264 Package
- **FAST RECOVERY BODY DIODE**



MAXIMUM RATINGS

All Ratings: $T_C = 25^\circ\text{C}$ unless otherwise specified.

Symbol	Parameter	APT10035	UNIT
V_{DSS}	Drain-Source Voltage	1000	Volts
I_D	Continuous Drain Current @ $T_C = 25^\circ\text{C}$	28	Amps
I_{DM}	Pulsed Drain Current ^①	112	
V_{GS}	Gate-Source Voltage Continuous	± 30	Volts
V_{GSM}	Gate-Source Voltage Transient	± 40	
P_D	Total Power Dissipation @ $T_C = 25^\circ\text{C}$	690	Watts
	Linear Derating Factor	5.5	W/ $^\circ\text{C}$
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-55 to 150	$^\circ\text{C}$
T_L	Lead Temperature: 0.063" from Case for 10 Sec.	300	
I_{AR}	Avalanche Current ^① (Repetitive and Non-Repetitive)	28	Amps
E_{AR}	Repetitive Avalanche Energy ^①	50	mJ
E_{AS}	Single Pulse Avalanche Energy ^④	3000	

STATIC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
BV_{DSS}	Drain-Source Breakdown Voltage ($V_{GS} = 0V, I_D = 250\mu A$)	1000			Volts
$I_{D(on)}$	On State Drain Current ^② ($V_{DS} > I_{D(on)} \times R_{DS(on)}$ Max, $V_{GS} = 10V$)	28			Amps
$R_{DS(on)}$	Drain-Source On-State Resistance ^② ($V_{GS} = 10V, 14A$)			0.37	Ohms
I_{DSS}	Zero Gate Voltage Drain Current ($V_{DS} = 1000V, V_{GS} = 0V$)			250	μA
	Zero Gate Voltage Drain Current ($V_{DS} = 800V, V_{GS} = 0V, T_C = 125^\circ\text{C}$)			1000	
I_{GSS}	Gate-Source Leakage Current ($V_{GS} = \pm 30V, V_{DS} = 0V$)			± 100	nA
$V_{GS(th)}$	Gate Threshold Voltage ($V_{DS} = V_{GS}, I_D = 2.5mA$)	3		5	Volts

 **CAUTION:** These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

APT Website - <http://www.advancedpower.com>

DYNAMIC CHARACTERISTICS

APT10035B2FLL -LFLL

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
C_{iss}	Input Capacitance	$V_{GS} = 0V$ $V_{DS} = 25V$ $f = 1\text{ MHz}$		5185		pF
C_{oss}	Output Capacitance			881		
C_{rss}	Reverse Transfer Capacitance			160		
Q_g	Total Gate Charge ③	$V_{GS} = 10V$ $V_{DD} = 500V$ $I_D = 28A @ 25^\circ C$		186		nC
Q_{gs}	Gate-Source Charge			24		
Q_{gd}	Gate-Drain ("Miller") Charge			122		
$t_{d(on)}$	Turn-on Delay Time	RESISTIVE SWITCHING $V_{GS} = 15V$ $V_{DD} = 500V$ $I_D = 28A @ 25^\circ C$ $R_G = 0.6\Omega$		12		ns
t_r	Rise Time			10		
$t_{d(off)}$	Turn-off Delay Time			36		
t_f	Fall Time			9		
E_{on}	Turn-on Switching Energy ⑥	INDUCTIVE SWITCHING @ 25°C $V_{DD} = 670V, V_{GS} = 15V$ $I_D = 28A, R_G = 5\Omega$		900		μJ
E_{off}	Turn-off Switching Energy			623		
E_{on}	Turn-on Switching Energy ⑥	INDUCTIVE SWITCHING @ 125°C $V_{DD} = 670V, V_{GS} = 15V$ $I_D = 28A, R_G = 5\Omega$		1423		
E_{off}	Turn-off Switching Energy			779		

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
I_S	Continuous Source Current (Body Diode)			28	Amps
I_{SM}	Pulsed Source Current ① (Body Diode)			112	
V_{SD}	Diode Forward Voltage ② ($V_{GS} = 0V, I_S = -28A$)			1.3	Volts
dv/dt	Peak Diode Recovery dv/dt ⑤			18	V/ns
t_{rr}	Reverse Recovery Time ($I_S = -28A, di/dt = 100A/\mu s$)	$T_j = 25^\circ C$		320	ns
		$T_j = 125^\circ C$		650	
Q_{rr}	Reverse Recovery Charge ($I_S = -28A, di/dt = 100A/\mu s$)	$T_j = 25^\circ C$	3.60		μC
		$T_j = 125^\circ C$	9.72		
I_{RRM}	Peak Recovery Current ($I_S = -28A, di/dt = 100A/\mu s$)	$T_j = 25^\circ C$	16.5		Amps
		$T_j = 125^\circ C$	24.7		

THERMAL CHARACTERISTICS

Symbol	Characteristic	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction to Case			0.18	$^\circ C/W$
$R_{\theta JA}$	Junction to Ambient			40	

① Repetitive Rating: Pulse width limited by maximum junction temperature

② Pulse Test: Pulse width < 380 μs , Duty Cycle < 2%

③ See MIL-STD-750 Method 3471

④ Starting $T_j = +25^\circ C$, $L = 7.65mH$, $R_G = 25\Omega$, Peak $I_L = 28A$

⑤ dv/dt numbers reflect the limitations of the test circuit rather than the device itself. $I_S \leq -I_{D28A}$ $di/dt \leq 700A/\mu s$ $V_R \leq V_{DSS}$ $T_j \leq 150^\circ C$

⑥ E_{on} includes diode reverse recovery. See figures 18, 20.

APT Reserves the right to change, without notice, the specifications and information contained herein.

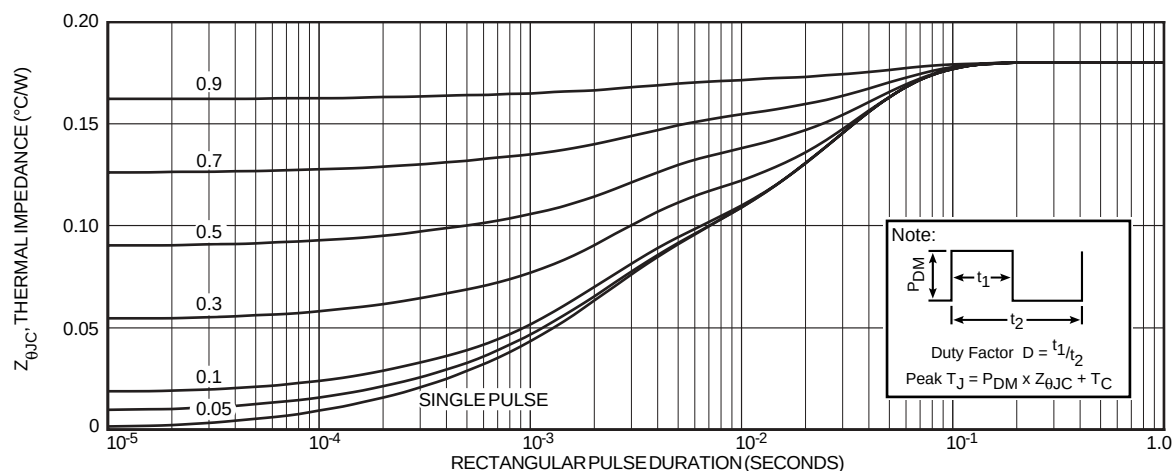


FIGURE 1, MAXIMUM EFFECTIVE TRANSIENT THERMAL IMPEDANCE, JUNCTION-TO-CASE vs PULSE DURATION

Typical Performance Curves

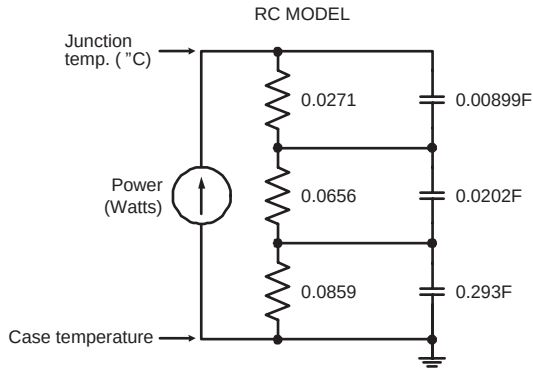


FIGURE2, TRANSIENT THERMAL IMPEDANCE MODEL

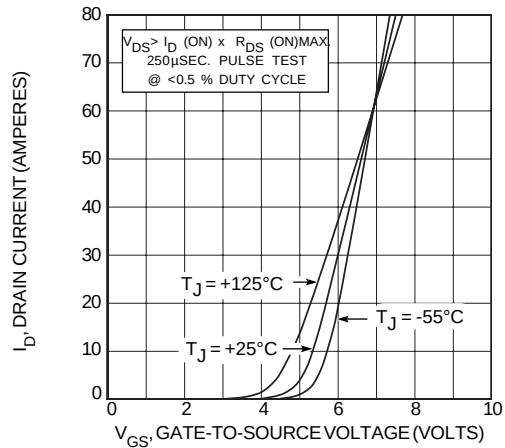


FIGURE4, TRANSFER CHARACTERISTICS

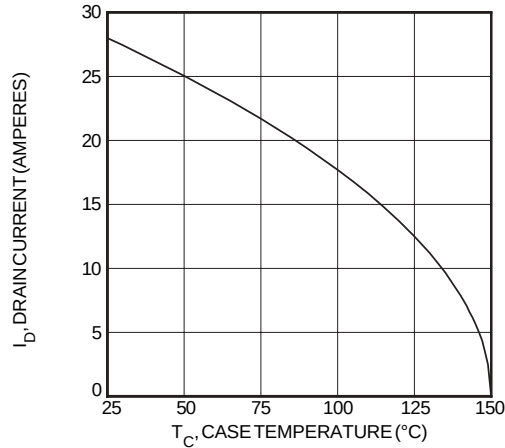


FIGURE6, MAXIMUM DRAIN CURRENT vs CASE TEMPERATURE

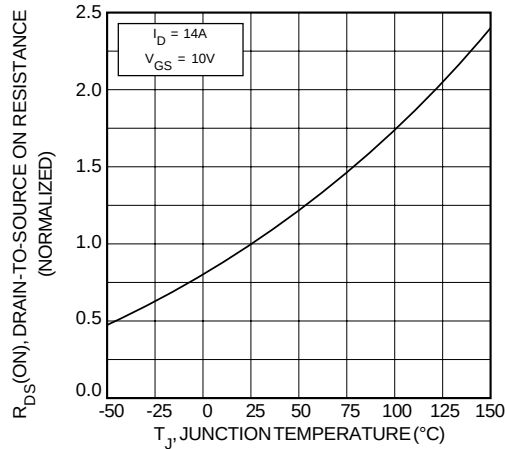


FIGURE8, ON-RESISTANCE vs. TEMPERATURE

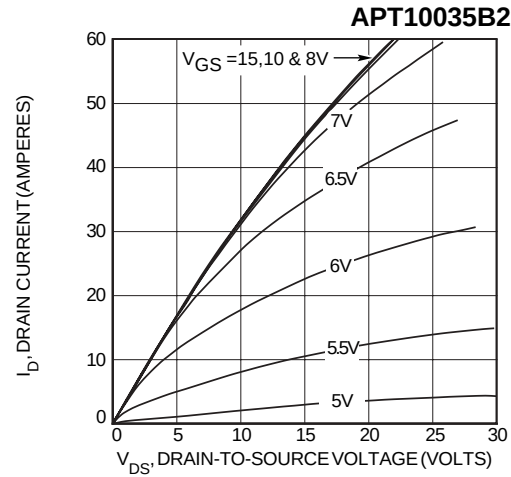


FIGURE3, LOW VOLTAGE OUTPUT CHARACTERISTICS

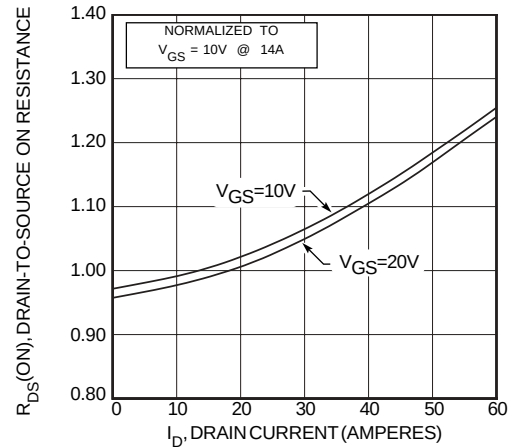


FIGURE5, $R_{DS}(\text{ON})$ vs DRAIN CURRENT

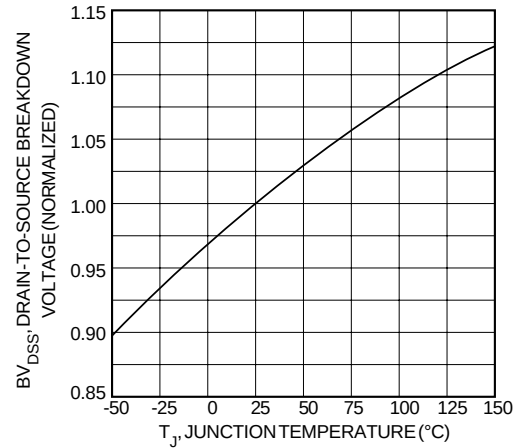


FIGURE7, BREAKDOWN VOLTAGE vs TEMPERATURE

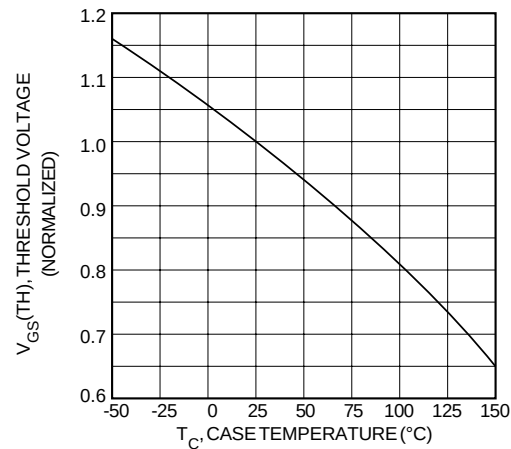


FIGURE9, THRESHOLD VOLTAGE vs TEMPERATURE

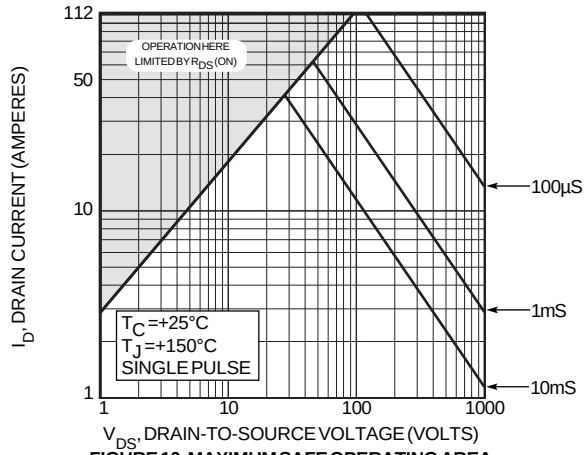


FIGURE 10, MAXIMUM SAFE OPERATING AREA

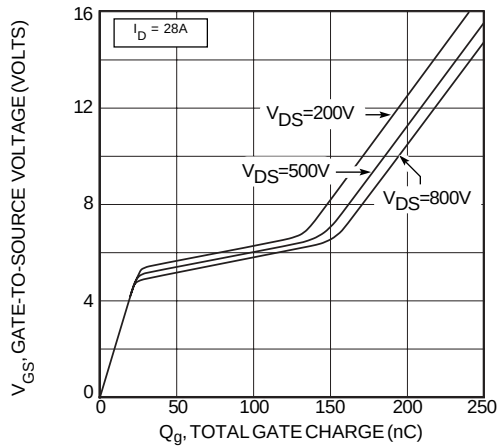


FIGURE 12, GATE CHARGES vs GATE-TO-SOURCE VOLTAGE

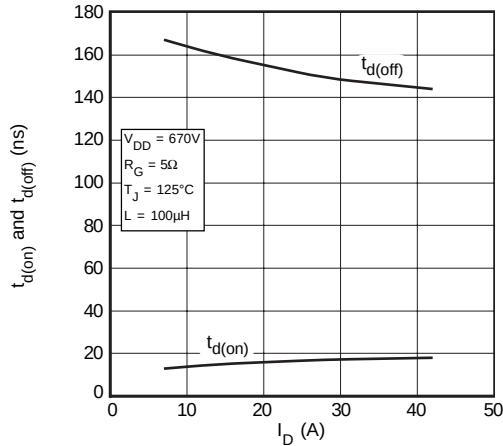


FIGURE 14, DELAY TIMES vs CURRENT

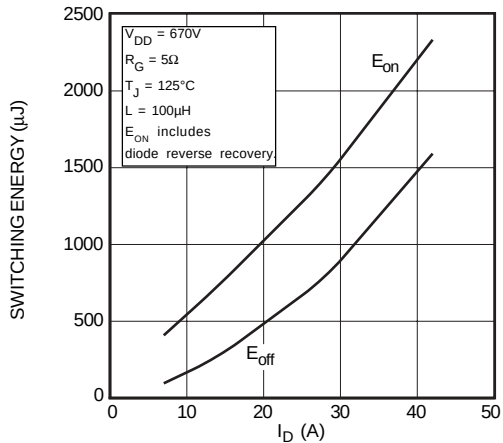


FIGURE 16, SWITCHING ENERGY vs CURRENT

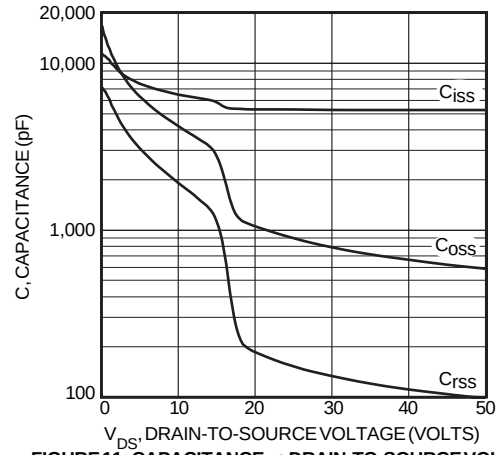


FIGURE 11, CAPACITANCE vs DRAIN-TO-SOURCE VOLTAGE

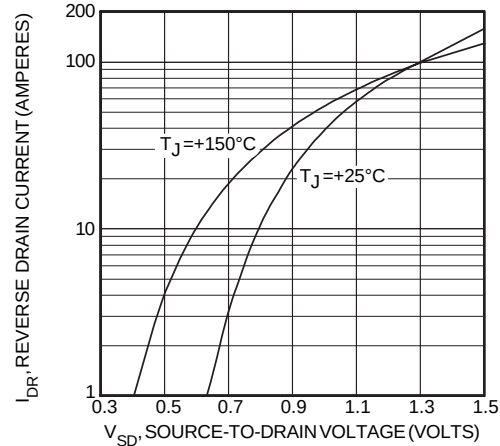


FIGURE 13, SOURCE-DRAIN DIODE FORWARD VOLTAGE

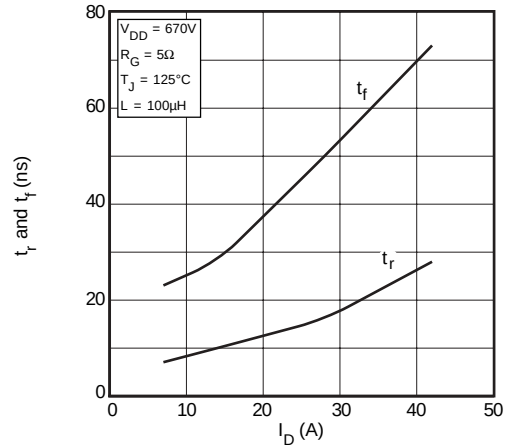


FIGURE 15, RISE AND FALL TIMES vs CURRENT

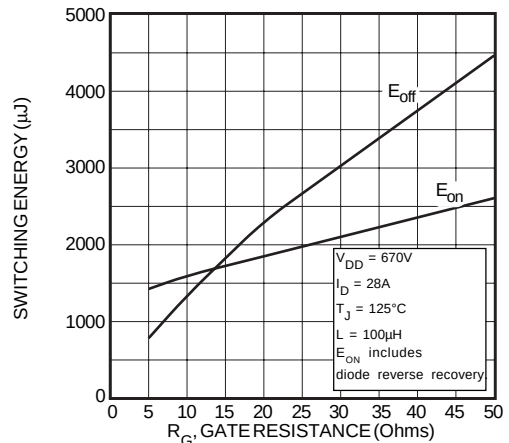


FIGURE 17, SWITCHING ENERGY vs. GATE RESISTANCE

AP110035B2FLL-LFEL

Top: 20.0 V, 1.00 V/div, 20.0 ns/div

Gate Voltage

Drain Voltage

Drain Current

Switching Energy

$t_{d(off)}$

t_f

90%

10%

0

27.2 V

20.8 V

0 A

$T_j = 125\text{ C}$

24 feb 2003 15:16:53

The diagram shows a power electronic circuit. A DC voltage source V_{DD} is connected to a decoupling capacitor. The positive terminal of the capacitor is connected to an inductor. The other end of the inductor is connected to the anode of a diode labeled APT15DF120B. The cathode of the diode is connected to a load labeled D.U.T. (Device Under Test). A ground symbol is connected to the other end of the D.U.T. Two measurement points are indicated: I_C (Collector Current) is measured across the D.U.T., and V_{CE} (Collector-Emitter Voltage) is measured across the diode.

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